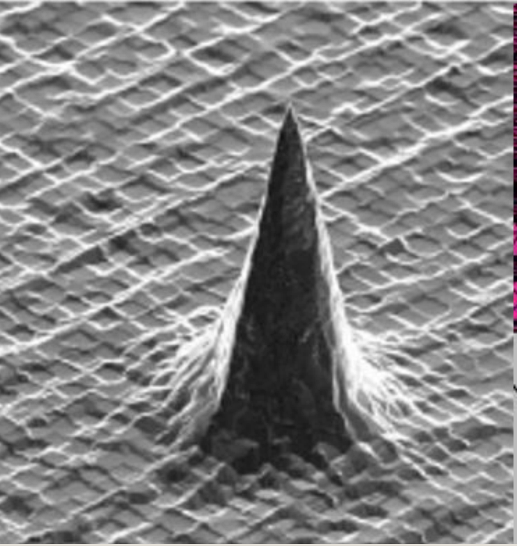
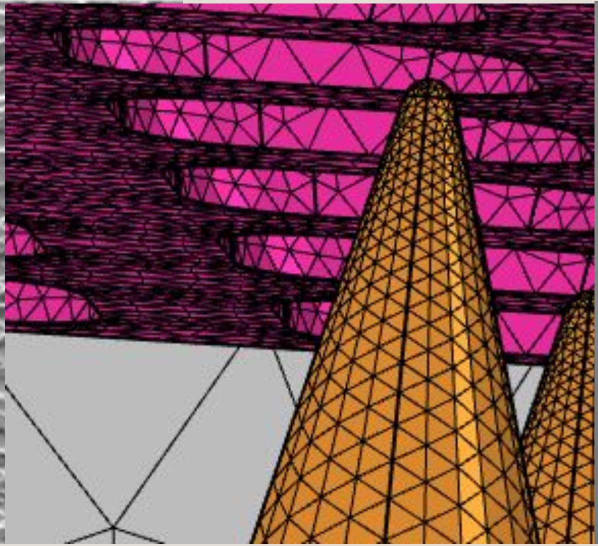
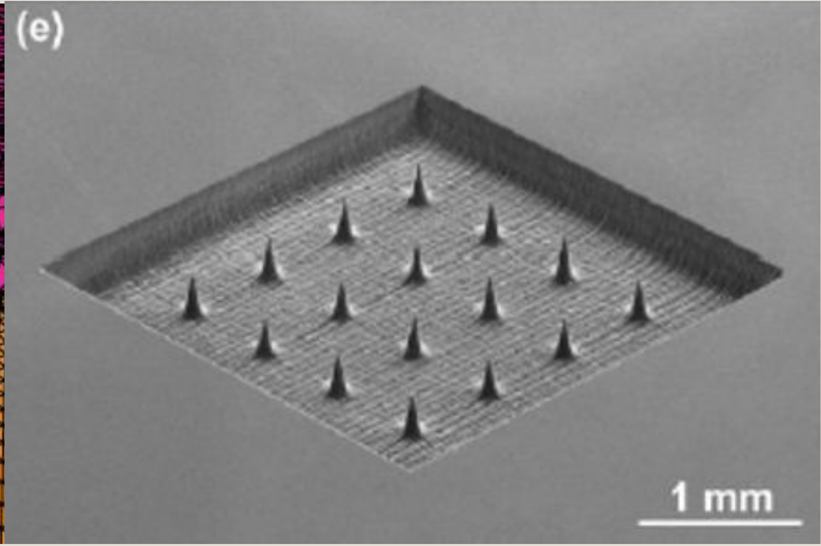






LPNHE PARIS
ILANCE

Romain Gaïor

LPNHE

2025/06/07
GDR DUPHY

UTokyo

K. Martens
M. Yamashita
C. Ishikawa
X. Wang

OTH REGENSBURG

Prof R. Schreiner
M. Hausladen

Universität Münster

Prof C. Weinheimer

Fea In XE Detector

Scientific context

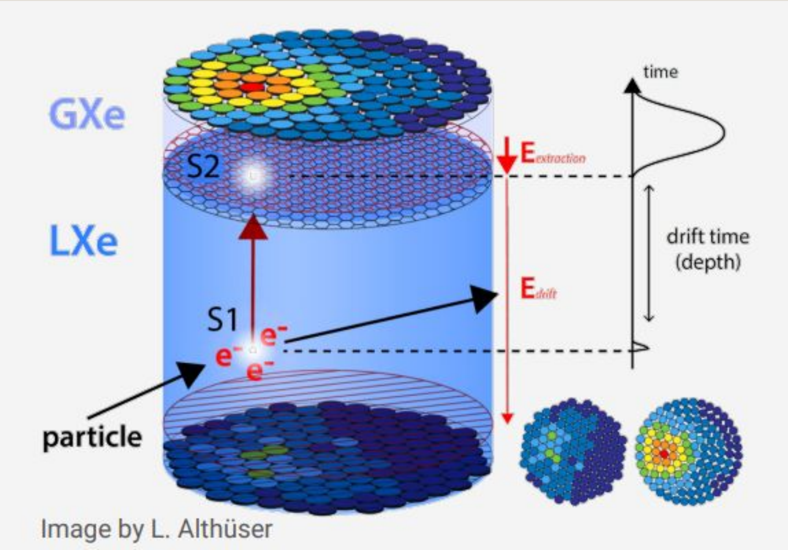
XLZD : Next generation LXe Experiment (50-100 tons) for **rare event searches** (Dark Matter, neutrinos, 0vBB)

(some)Problematics with large detectors

- Radioactive purity: need for faster **purification** methods (Radon)
- Electrodes for **2nd scintillation**:
  Mechanical issues, resolution, spurious charge

FEA: Microscopic Conductive structure

- **Large electric field** site
- Various shape / material (Cu, Si) / fabrication method
- Used in industry in vacuum



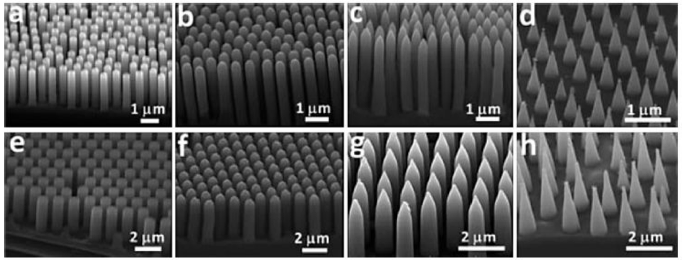
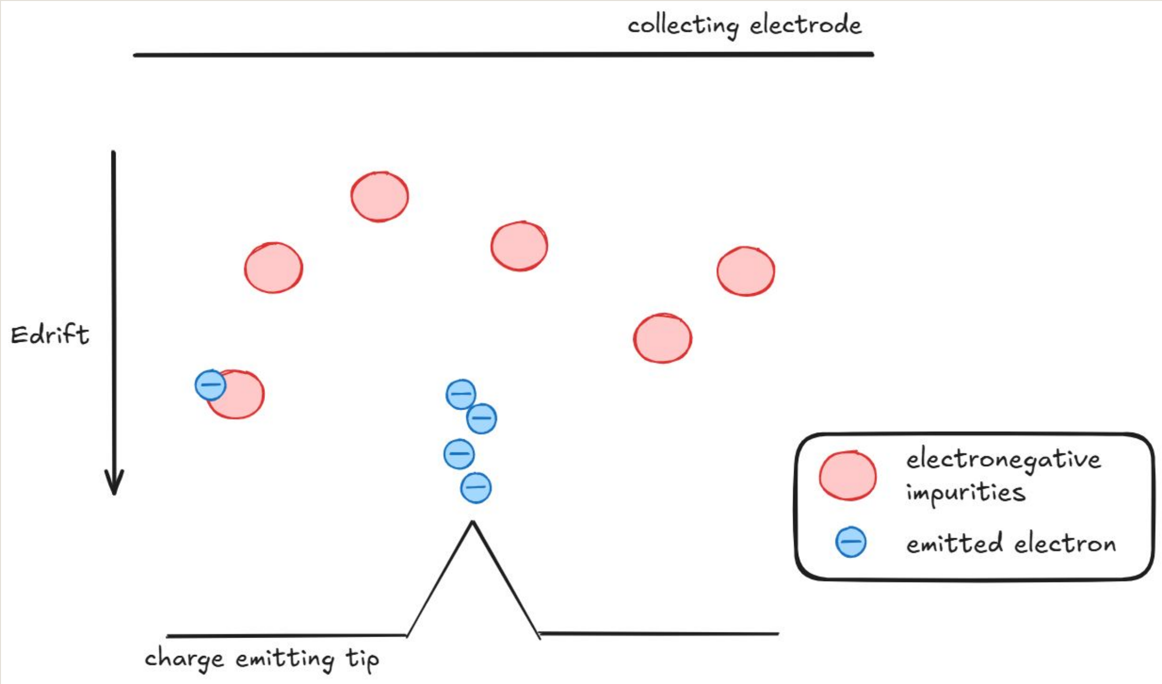
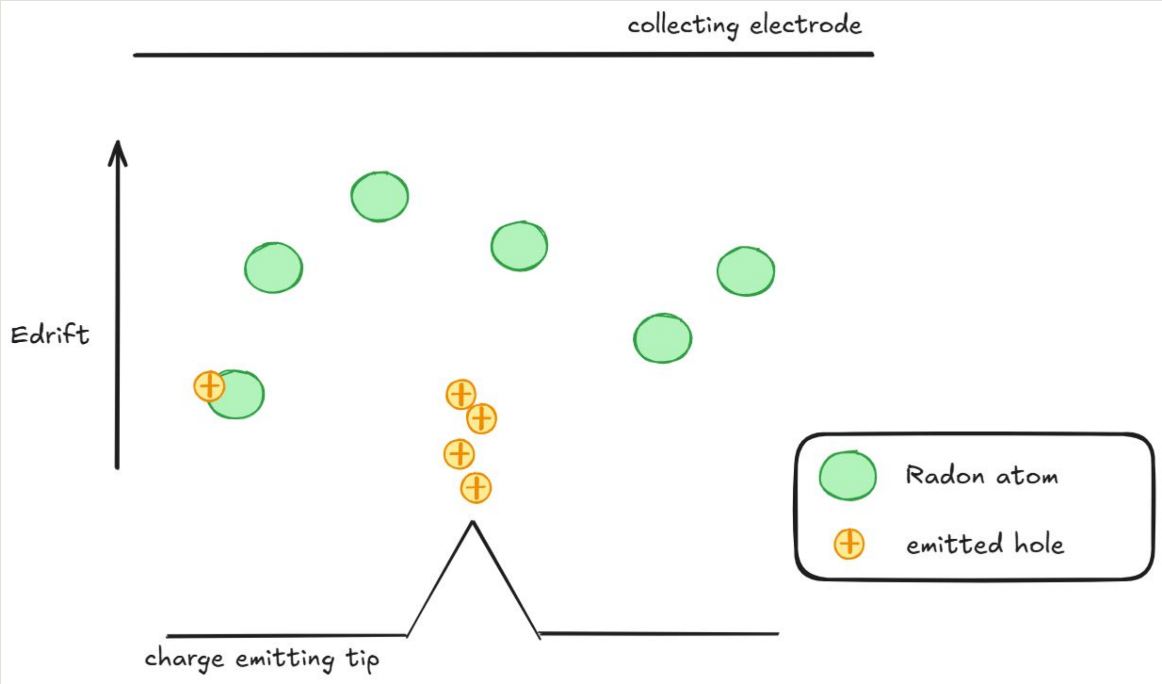


Figure 14. SEM images of highly regular (a and e) nanopillar, (b and f) nanorod, (c and g) nanopencil, and (d and h) nanocone Si arrays, produced by wet-etching. (Reproduced from ref. [81] with permission from the authors and the Royal Society of Chemistry).

PURIFICATION

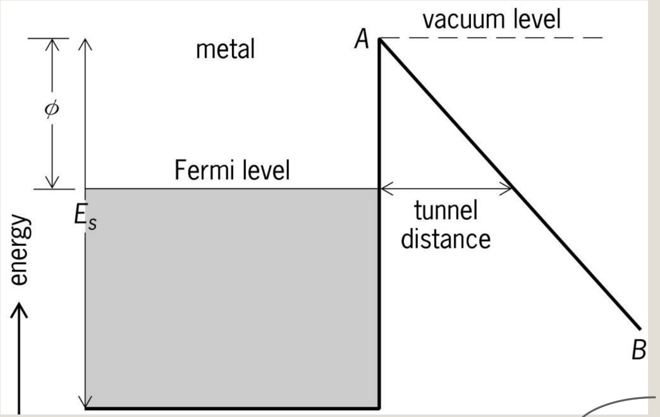


PURIFICATION



Field effect charge emission

Fowler-Nordheim tunneling (~1930)



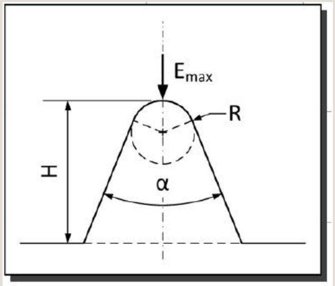
~ 10^9V/m

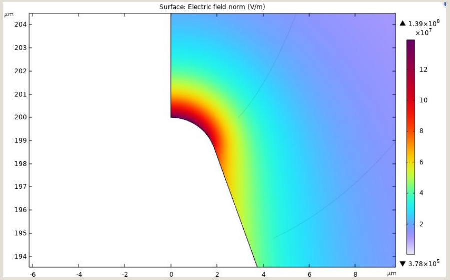
$$j = \frac{q^3}{2\pi h} \cdot \frac{\sqrt{\mu}}{(\phi + \mu)\sqrt{\phi}} \cdot F_l^2 \exp\left(-\frac{4\kappa\phi^{3/2}}{3qF_l}\right)$$

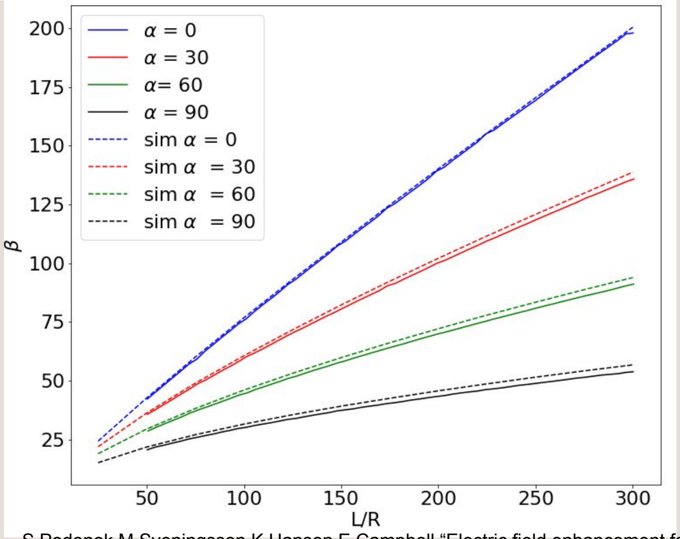
F_l=Electric surface field

Very high local field required

Field enhancement β





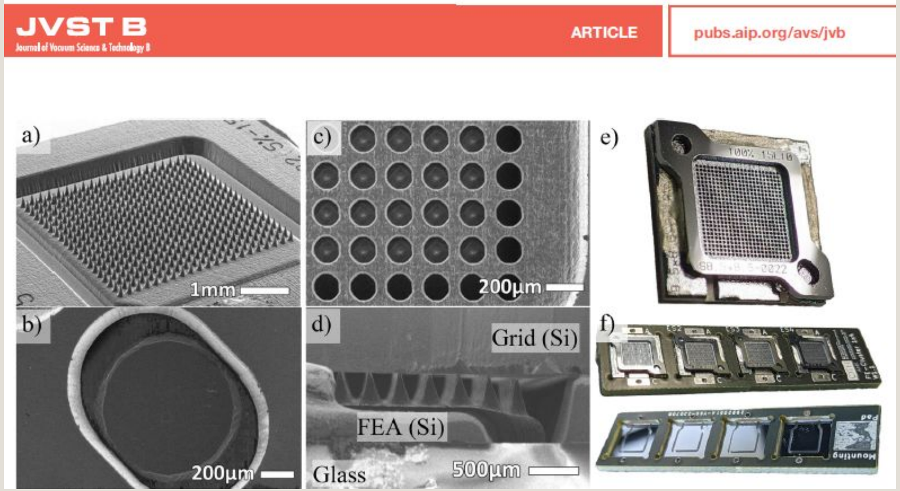


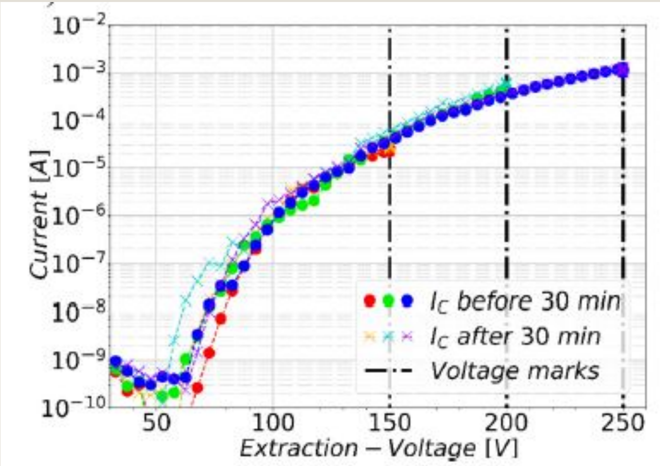
S.Podenok,M.Sveningsson,K.Hansen,E.Campbell,“Electric field enhancement factor around a metallic,end-capped cylinder”,NANO1(1),S.87-93(2006).

Charge emission in vacuum

Result from OTH in Vacuum

Hausladen *et al.* DOI: 10.1116/6.0003233

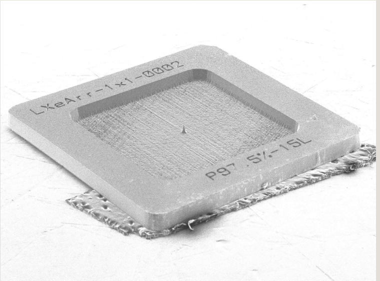


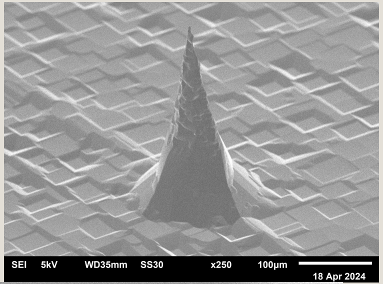


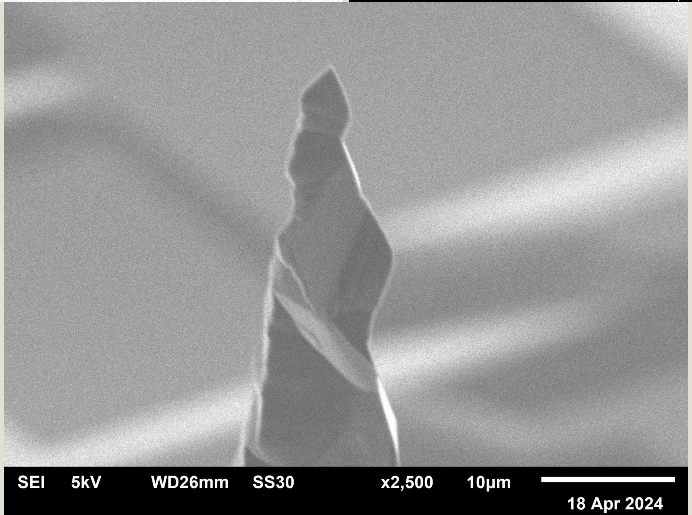
- Silicon laser micromachined tip array of 21x21
- Onset voltage of ~70V
- Stable current obtained
- Current distributed evenly over the array

Single tip in LXe

Tip for LXe tests







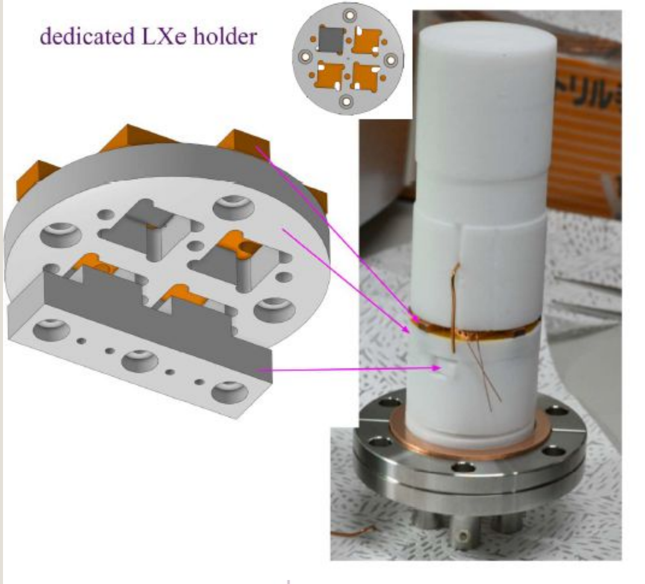
- We took first measurement in 2023 with a 21x21 array
  → Emission but hard to interpret

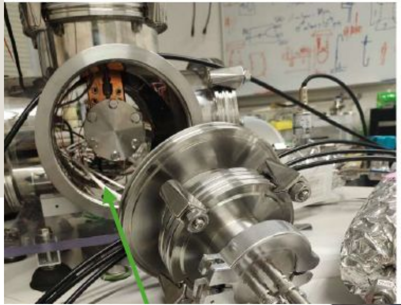
- Going back to 1 single tip

- First "conditioning" in vacuum
  → smoothens the surface

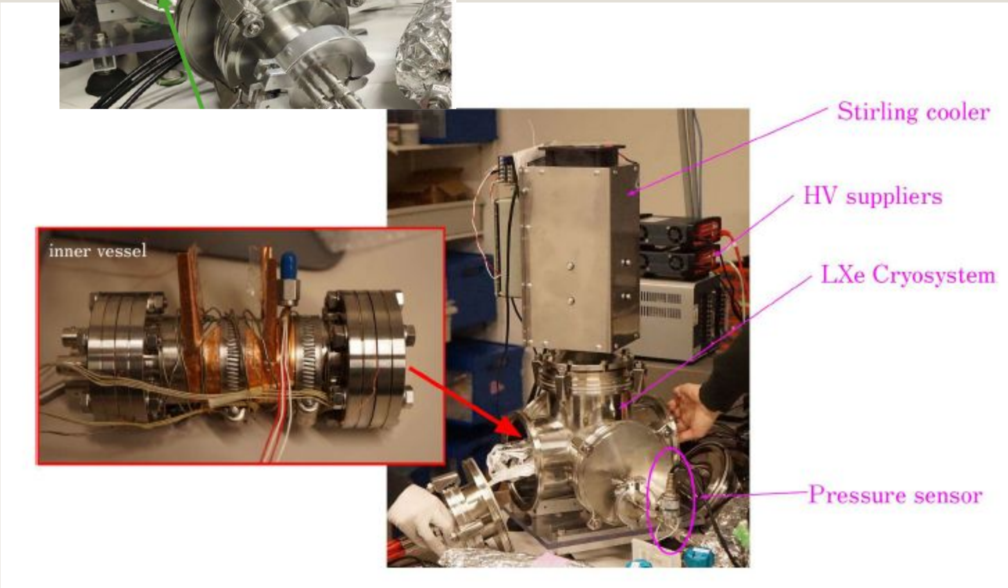
Single tip in LXe

Inner vessel





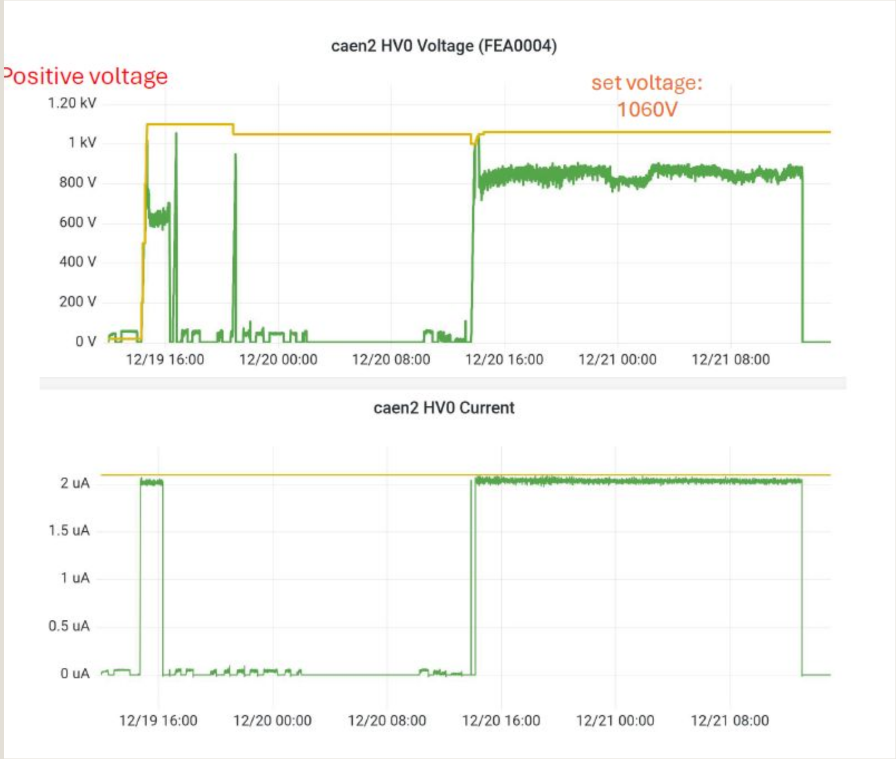
Cryogenic Setup

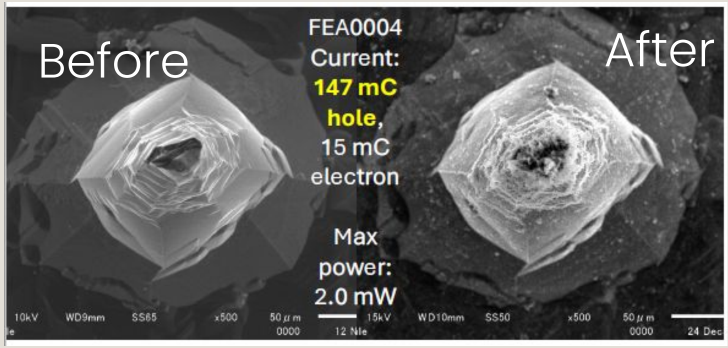


C. Ishikawa & X. Wang

Results

Electron AND Hole emission observed !



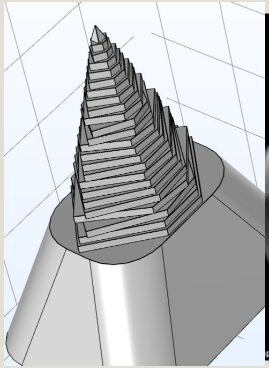


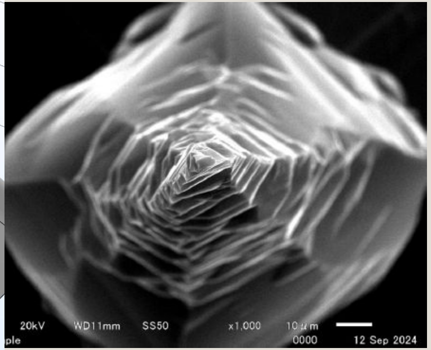
- Established procedure to obtain stable emission
- Change of tip structure observed to be understood
- Effect of coating ?

C. Ishikawa & X. Wang

Plans

- Experience building up on the tip conditioning
- Work on simulations is ongoing
- Distribute emission over an array
- Measure attachment to radon with a dedicated experiment →





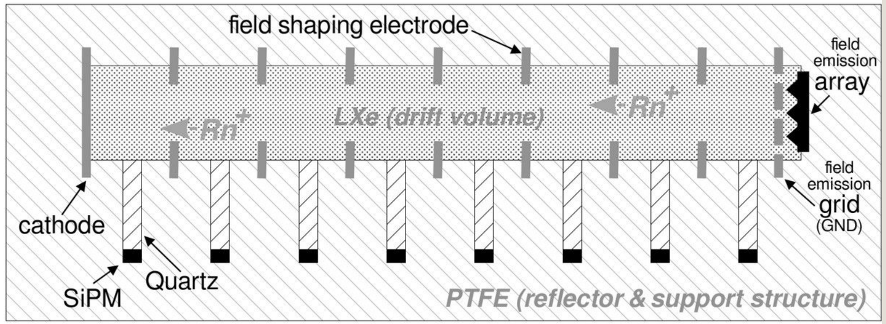
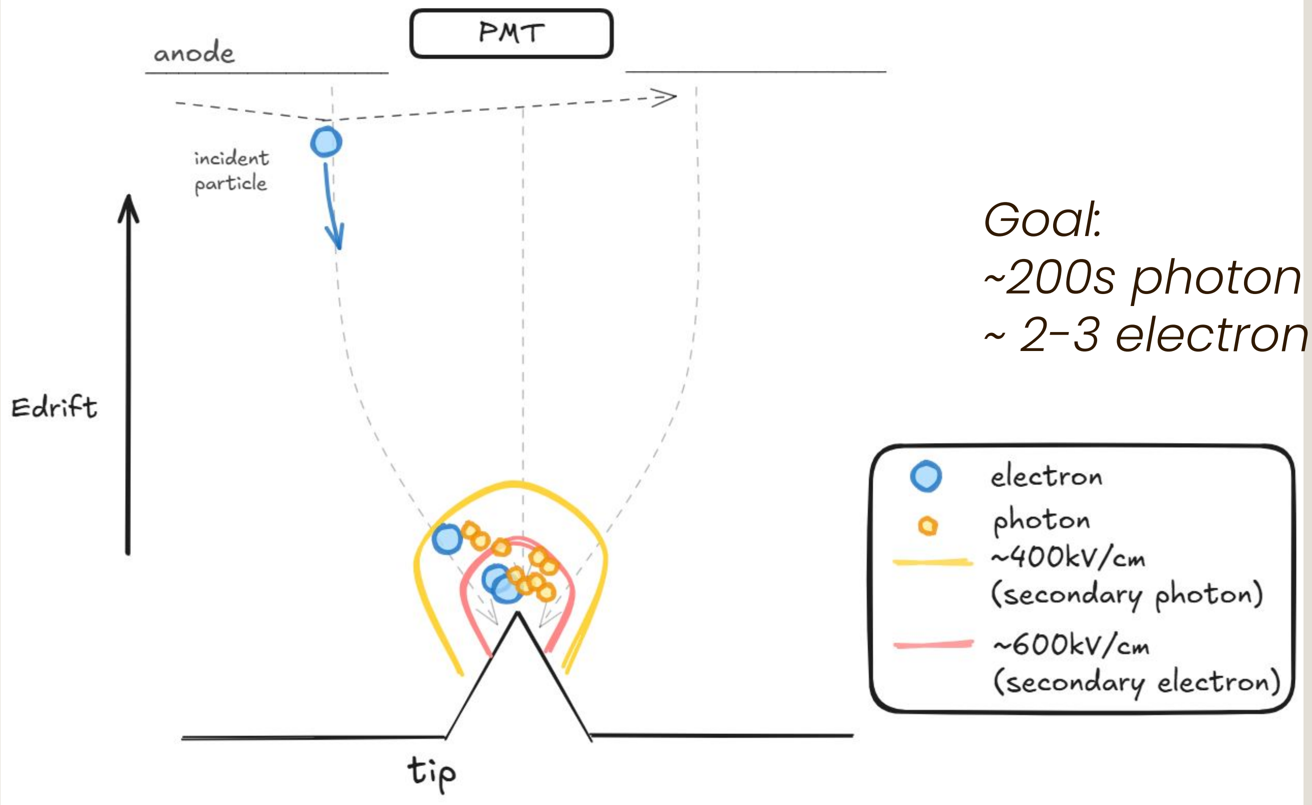


Fig. 1 Schematic of LXe drift volume

K. Martens credit

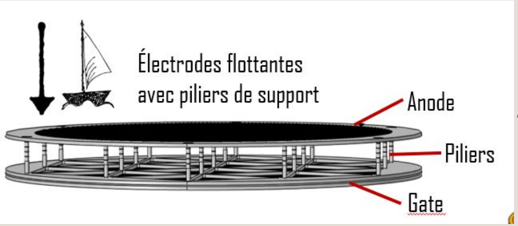
Secondary scintillation



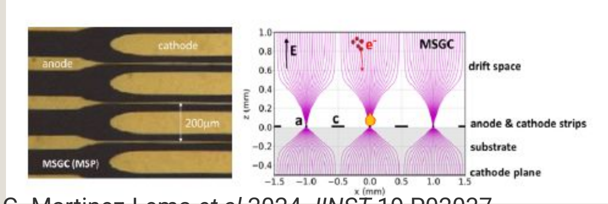
Goal:
~200s photon
~ 2-3 electron

Electrode R&Ds

Double phase “Floating electrodes”

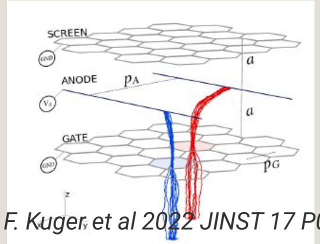


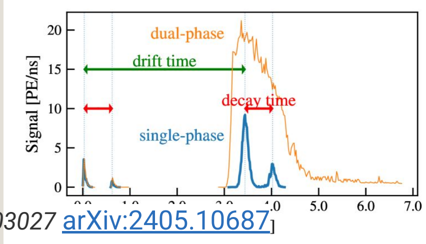
Single phase Microstrips



G. Martinez-Lema *et al* 2024 *JINST* 19 P02037

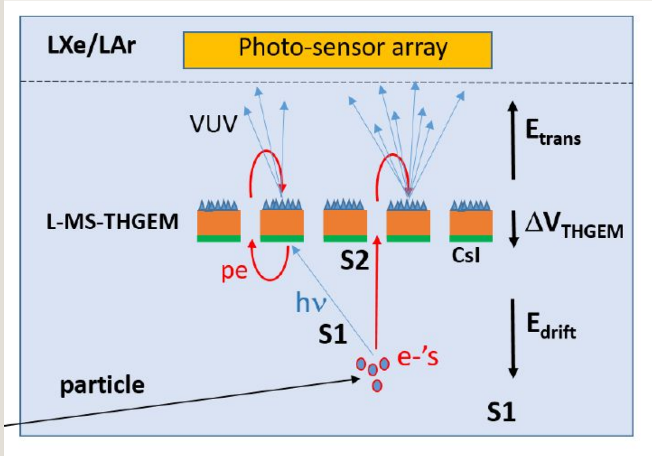
Single phase with wire





F. Kuger et al 2022 JINST 17 P03027 [arXiv:2405.10687]

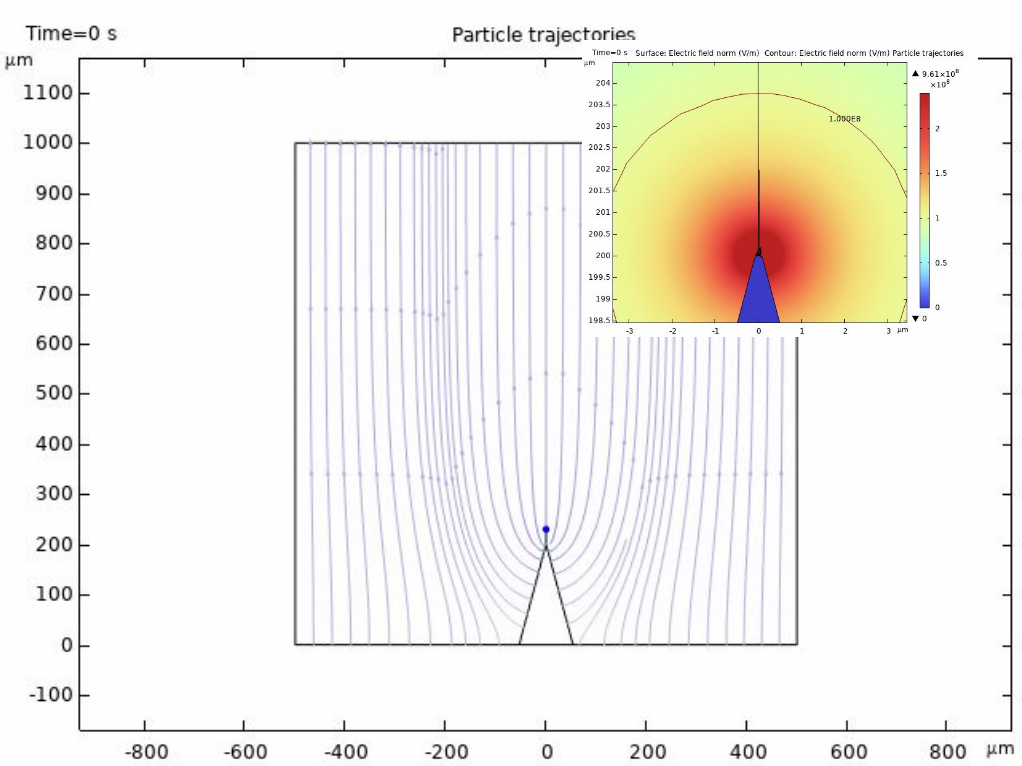
Single phase with micro/nano structure



A. Breskin 2022 *JINST* 17 P08002 / arXiv:2203.01774

- **No liquid - gas interface**
- **No electrode sagging**
- **No delayed electrons**
- **Cleaner S2 signal**
- **Large local electric field**
- **Not as studied as double phase for rare event searches**

Secondary scintillation simulation



1. E-field simulation
2. Electron tracking
3. Emission simulation

$$\Delta N_e = N_e \theta_0 \exp\left(-\frac{\theta_1}{E(\vec{x}, V_A, d_w) - \theta_2}\right)\Delta\vec{x},$$

$$\Delta N_\gamma = N_e \theta_3 (E(\vec{x}, V_A, d_w) - \theta_4)\Delta\vec{x},$$

θ_2= 400 kV/cm

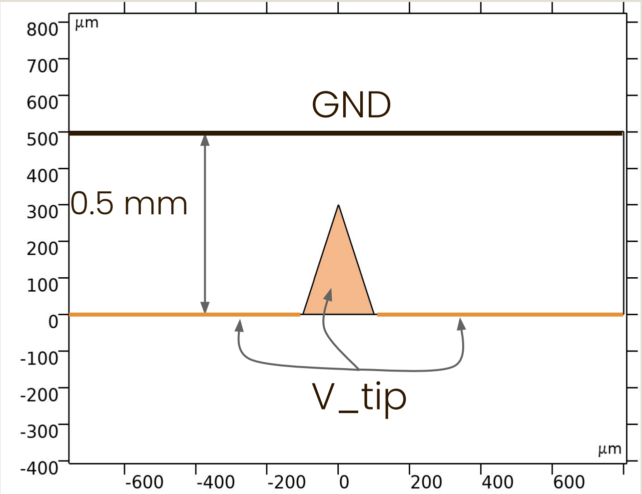
θ_4= 600 kV/cm

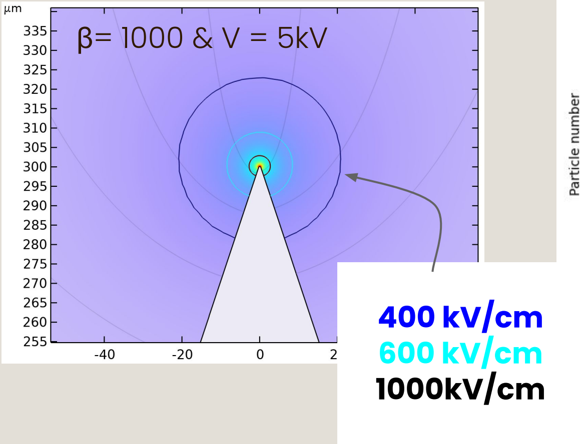
arXiv:1408.6206v3 / E Aprile *et al* 2014 *JINST* 9 P11012

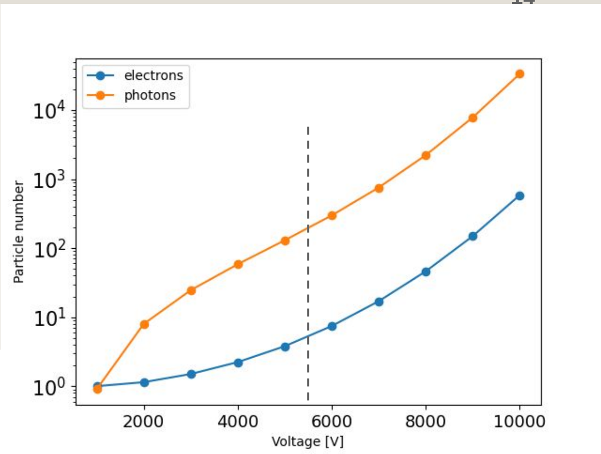
→ Started with full COMSOL

→ Now Emission with python code

Simple geometry



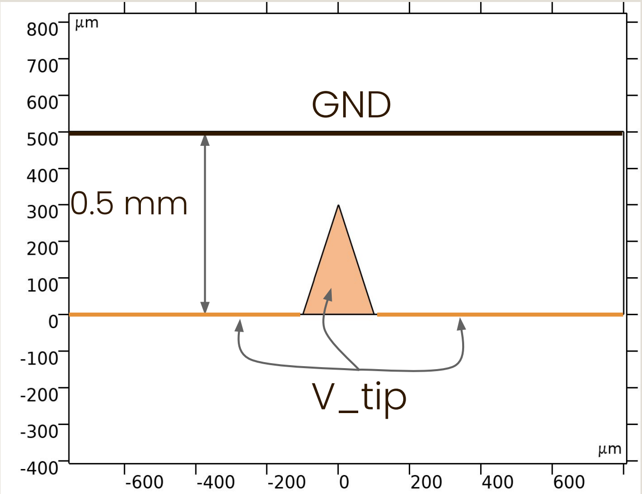


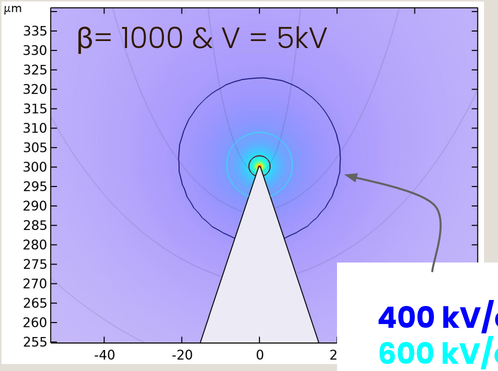


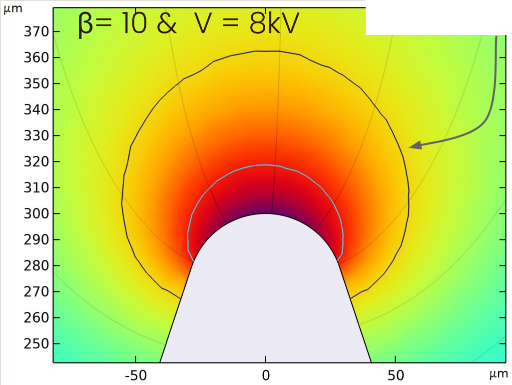
- Number of electron vs photon
- Charge emission ?

→ Need a smaller enhancement factor

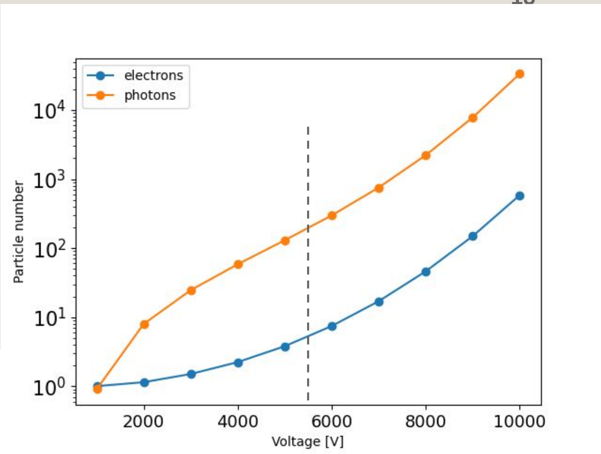
Simple geometry

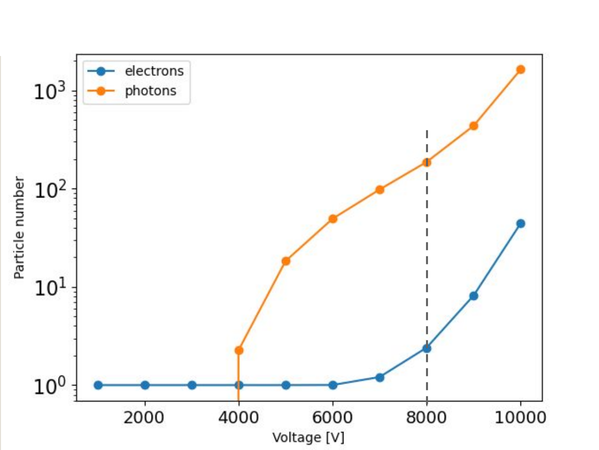






400 kV/cm
600 kV/cm
1000kV/cm



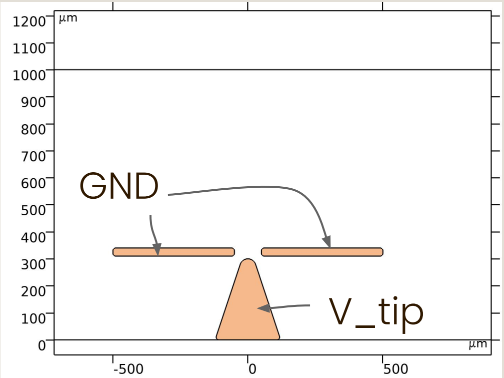


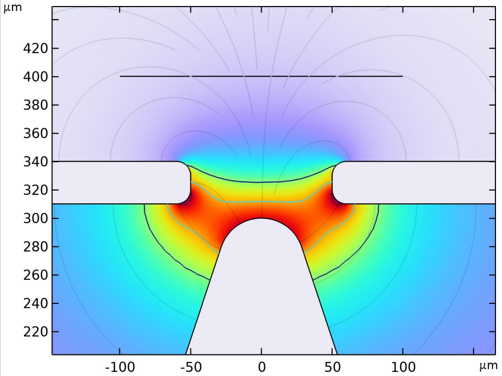
- Number of electron vs photon
- Charge emission ?

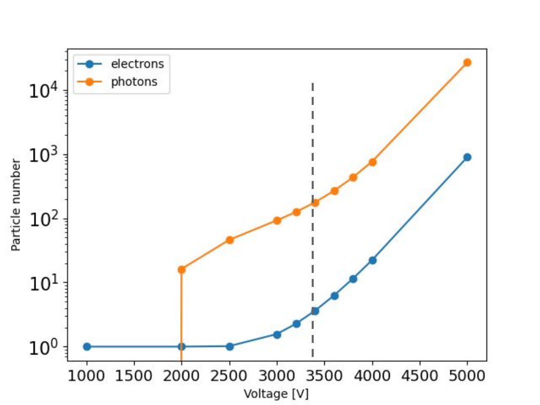
→ Need a smaller enhancement factor

Many possibilities

Gated FEA

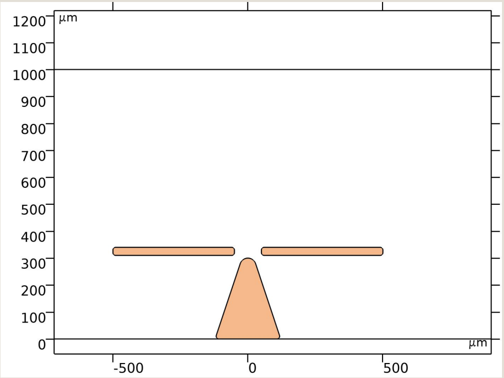


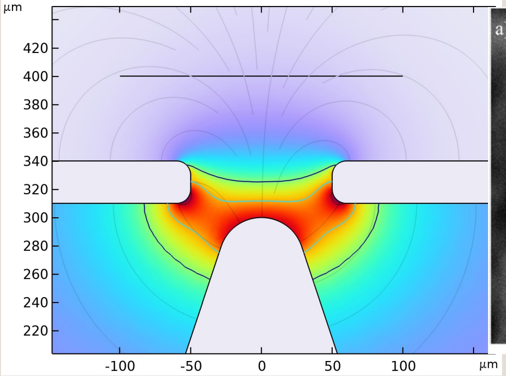


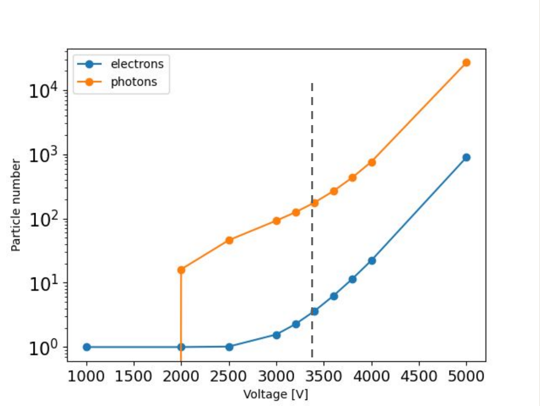


Many possibilities

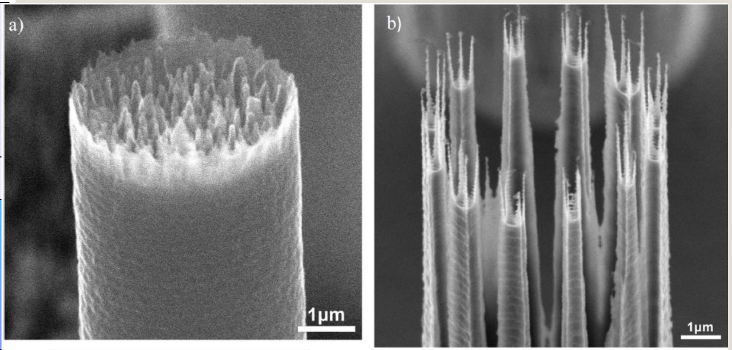
Gated FEA

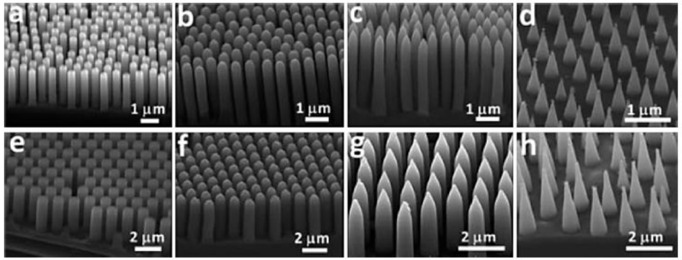






Various geometry





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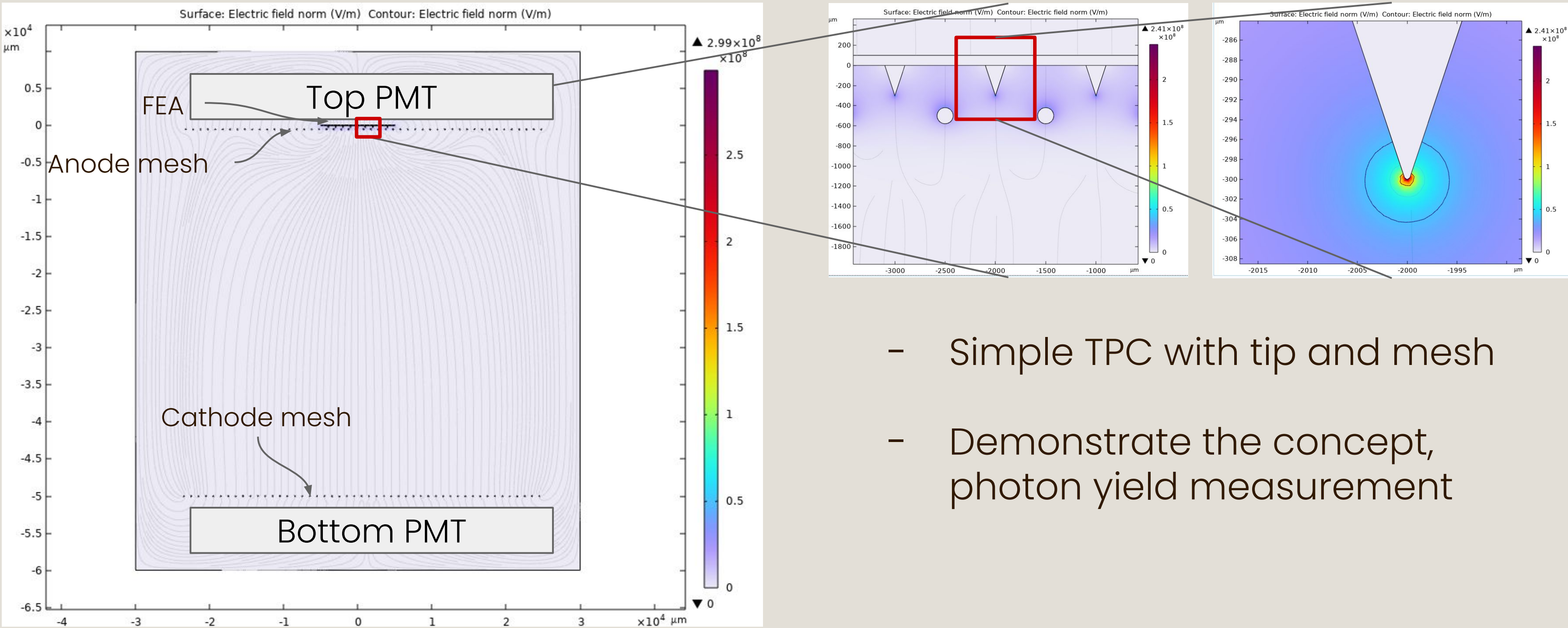
INTRO
CHARGE EMISSION
SECONDARY SCINTILLATION
CONCLUSION

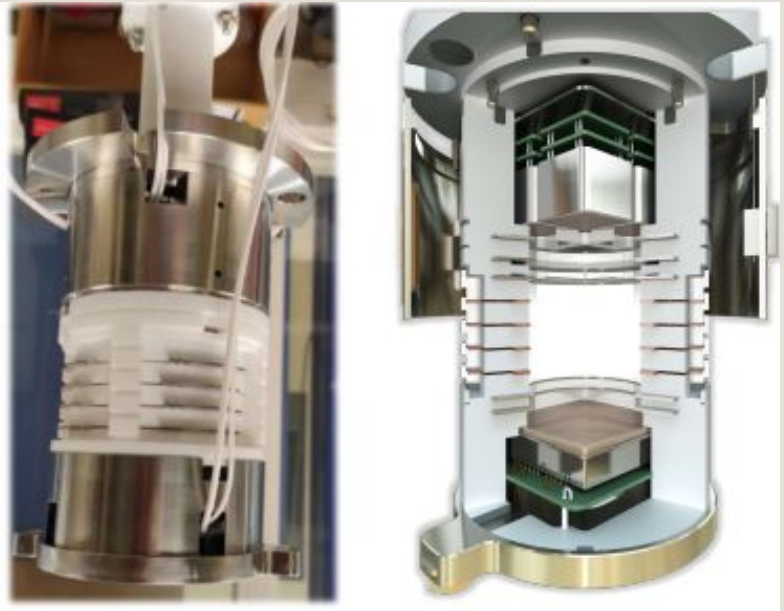
Simple Tip+Mesh TPC

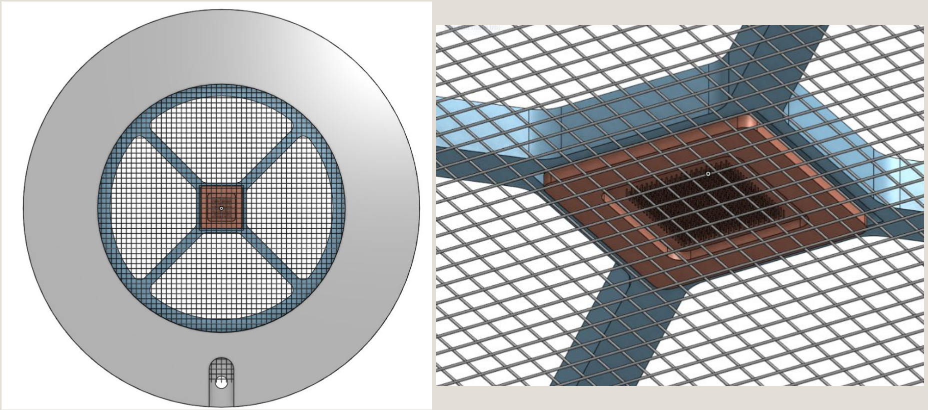


- Simple TPC with tip and mesh
- Demonstrate the concept, photon yield measurement

Simple Tip+Mesh TPC

INTRO
CHARGE EMISSION
SECONDARY SCINTILLATION
CONCLUSION





- Simple adaptation of Xelab
- Gate + Anode → FEA + Anode

Plans

- Explore / optimize geometries with simulation
  - among existing ones
  - discuss feasibility if not existing
- Test simulation with experiment
  → Xelab@LPNHE is now an option
- Measure performances of these structures